

Features

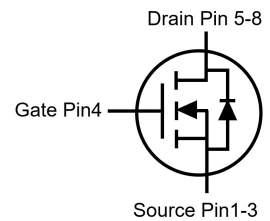
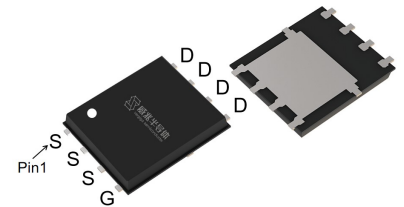
- Enhancement mode
- Ultra Low RDS(on) to minimize conduction losses
- VitoMOS® II Technology
- 100% Avalanche tested, 100% Rg tested
- Optimized Qg, Qgd, and Qgd/Qgs ratio to minimize switching losses



Halogen-Free

Part ID	Package Type	Marking	Packing
VS3896GPMT	PDFN5060X	3896GPMT	3000pcs/Reel

PDFN5060X



Maximum ratings, at T_A =25°C, unless otherwise specified

Symbol	Parameter		Rating	Unit
V(BR)DSS	Drain-source breakdown voltage		30	V
VGS	Gate-source voltage		±20	V
IS	Diode continuous forward current	T _C =25°C	284	A
ID	Continuous drain current @VGS=10V (Silicon limited)	T _C = 25°C	600	A
ID	Continuous drain current @VGS=10V (Silicon limited)	T _C = 100°C	379	A
IDM	Pulse drain current tested ①	T _C =25°C	1100	A
IDSM	Continuous drain current @VGS=10V	T _A =25°C	57	A
		T _A =70°C	46	A
EAS	Maximum avalanche energy, single pulsed ②		1406	mJ
PD	Maximum power dissipation ③	T _C =25°C	284	W
		T _C =100°C	114	W
PDSM	Maximum power dissipation ④	T _A =25°C	2.6	W
		T _A =70°C	1.7	W
TJ,TSTG	Operating junction and storage temperature range		-55 to 150	°C

Thermal characteristics

Symbol	Parameter	Typical	Max	Unit
RθJC	Thermal resistance, junction-to-case ⑤	0.37	0.44	°C/W
RθJA	Thermal resistance, junction-to-ambient ⑥	40	48	°C/W

Electrical Characteristics

Symbol	Parameter	Condition	Min.	Typ.	Max.	Unit
Static Electrical Characteristics @ T _j =25°C (unless otherwise stated)						
V(BR)DSS	Drain-source breakdown voltage	V _{GS} =0V, I _D =250μA	30	--	--	V
I _{DSS}	Zero gate voltage drain current(T _j =25°C)	V _{DS} =30V,V _{GS} =0V	--	--	1	μA
	Zero gate voltage drain current(T _j =125°C)⑦	V _{DS} =30V,V _{GS} =0V	--	--	100	μA
I _{GSS}	Gate-body leakage current	V _{GS} =±20V,V _{DS} =0V	--	--	±100	nA
V _{GS(th)}	Gate threshold voltage	V _{DS} =V _{GS} ,I _D =250μA	1.1	1.6	2.2	V
R _{DS(on)}	Drain-source on-state resistance ⑧	V _{GS} =10V, I _D =40A	--	0.41	0.55	mΩ
		T _j =100°C ⑦	--	0.51	--	mΩ
R _{DS(on)}	Drain-source on-state resistance ⑧	V _{GS} =4.5V, I _D =30A	--	0.68	0.92	mΩ
G _{FS}	Forward transconductance	V _{DS} =5V, I _D =40A	--	184	--	S
Dynamic Electrical Characteristics @ T _j = 25°C (unless otherwise stated)						
C _{iss}	Input capacitance ⑦	V _{DS} =15V,V _{GS} =0V, f=100kHz	--	9590	--	pF
C _{oss}	Output capacitance ⑦		--	3065	--	pF
C _{rss}	Reverse transfer capacitance ⑦		--	335	--	pF
R _g	Gate resistance	f=1MHz	--	2.9	--	Ω
Q _g (10V)	Total gate charge ⑦	V _{DS} =15V,I _D =40A, V _{GS} =10V	--	145	--	nC
Q _g (4.5V)	Total gate charge ⑦		--	69	--	nC
Q _{gs}	Gate-source charge ⑦		--	27	--	nC
Q _{gd}	Gate-drain charge ⑦		--	23	--	nC
Switching Characteristics ⑦						
T _{d(on)}	Turn-on delay Time	V _{DD} =15V, I _D =40A, R _G =3Ω, V _{GS} =10V	--	11	--	ns
T _r	Turn-on rise Time		--	110	--	ns
T _{d(off)}	Turn-off delay Time		--	136	--	ns
T _f	Turn-off fall Time		--	71	--	ns
Source- Drain Diode Characteristics@ T _j = 25°C (unless otherwise stated)						
V _{SD}	Forward on voltage	I _{SD} =40A,V _{GS} =0V	--	0.75	1	V
T _{rr}	Reverse recovery time ⑦	V _{DD} =30V	--	51	--	ns
Q _{rr}	Reverse recovery charge ⑦	I _{sd} =40A, V _{GS} =0V di/dt=100A/μs	--	48	--	nC

NOTE:

① Single pulse; pulse width ≤ 100μs.

② This maximum value is based on starting T_j = 25°C, L = 0.5mH, R_G = 25Ω, I_{AS} = 75A, V_{GS} = 10V; 100% FT tested at L = 0.3mH, I_{AS} = 65A.

③ The power dissipation P_d is based on T_j(max), using junction-to-case thermal resistance RθJC.

④ The power dissipation P_{dsm} is based on T_j(max), using junction-to-ambient thermal resistance RθJA.

⑤ Thermal resistance from junction to soldering point (on the exposed drain pad). These tests are performed on a cold plate.

⑥ These tests are performed with the device mounted on 1 in2 FR-4 board with 2oz. Copper, in a still air environment with T_A=25°C.

⑦ Guaranteed by design, not subject to production testing.

⑧ Pulse width ≤ 380μs; duty cycles ≤ 2%.

Typical Characteristics

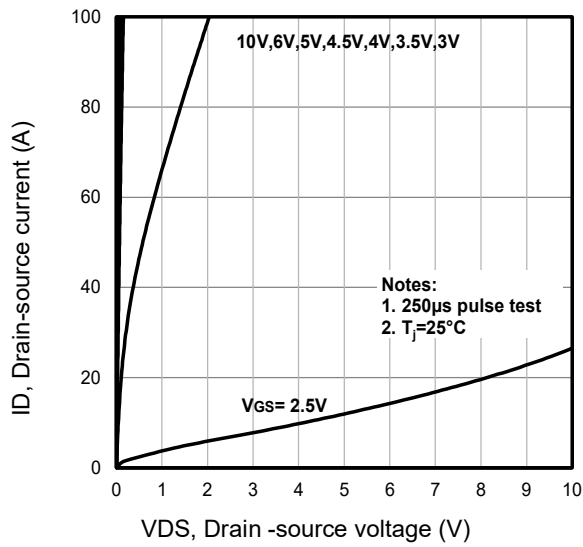


Fig1. Typical output characteristics

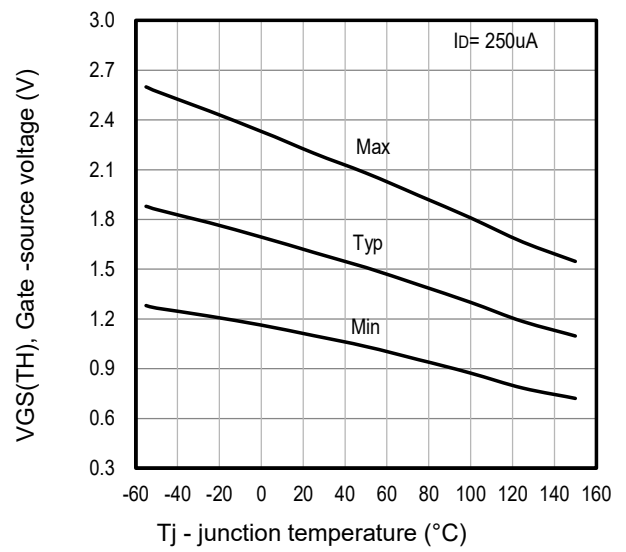


Fig2. Typical $V_{GS(TH)}$ gate-source voltage Vs. T_j

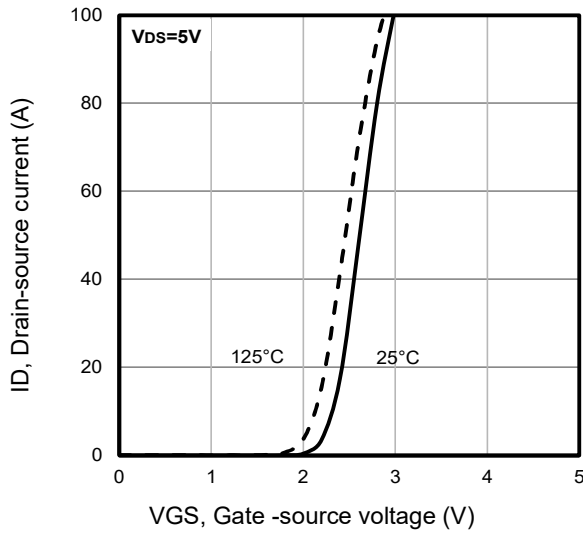


Fig3. Typical transfer characteristics

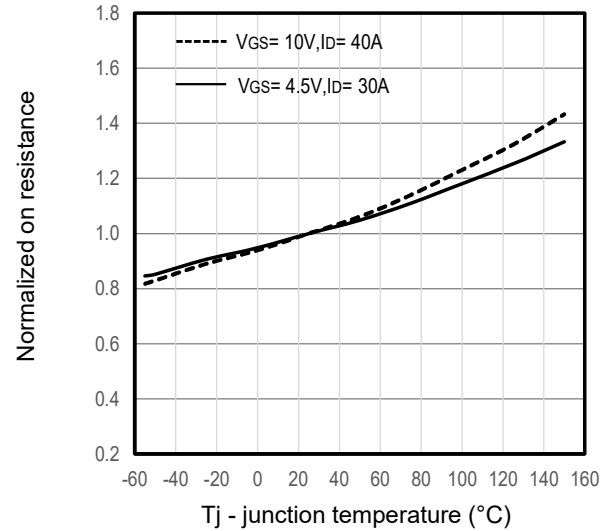


Fig4. Typical normalized on-resistance Vs. T_j

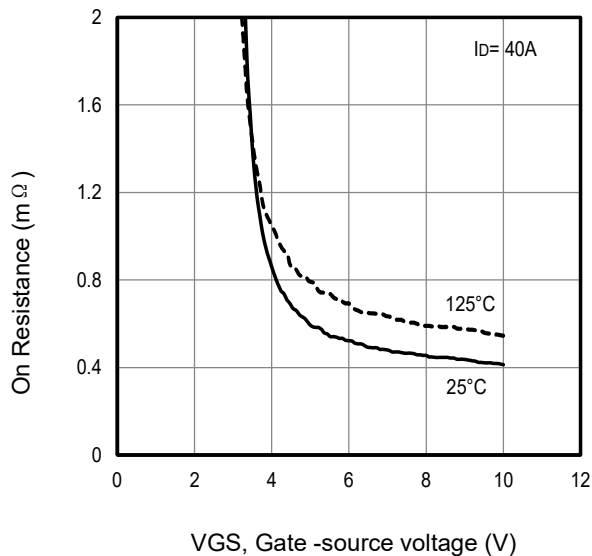


Fig5. Typical on resistance Vs gate-source voltage

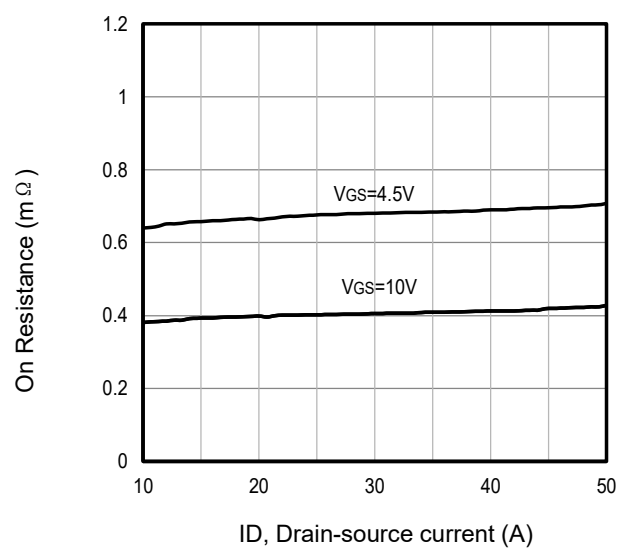


Fig6. Typical on resistance Vs drain current

Typical Characteristics

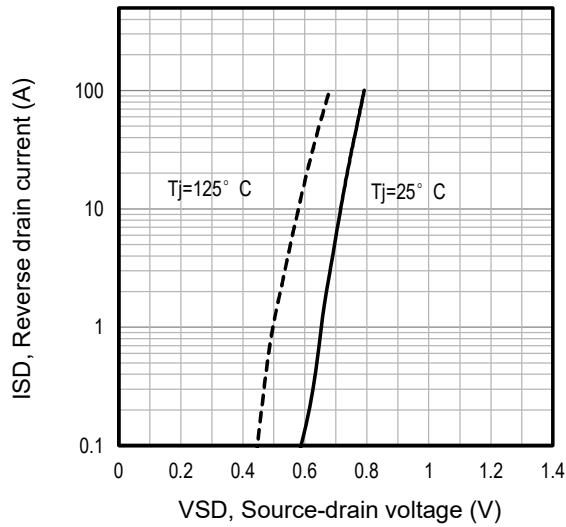


Fig7. Typical source-drain diode forward voltage

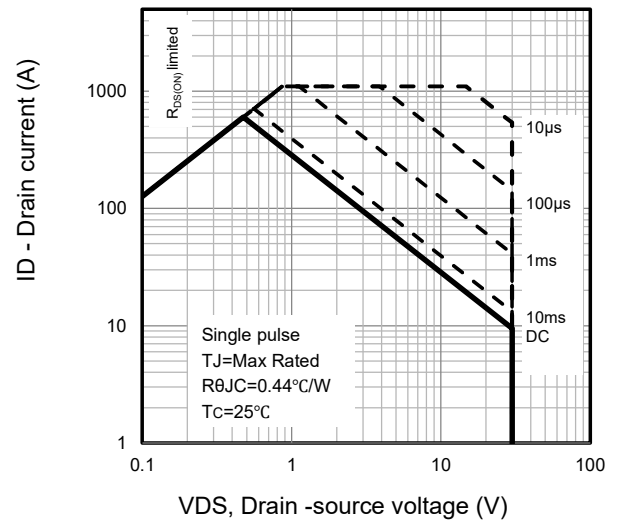


Fig8. Maximum safe operating area

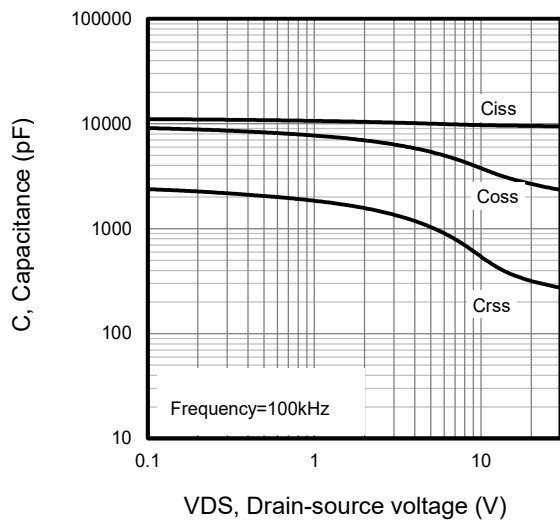


Fig9. Typical capacitance Vs. drain-source voltage

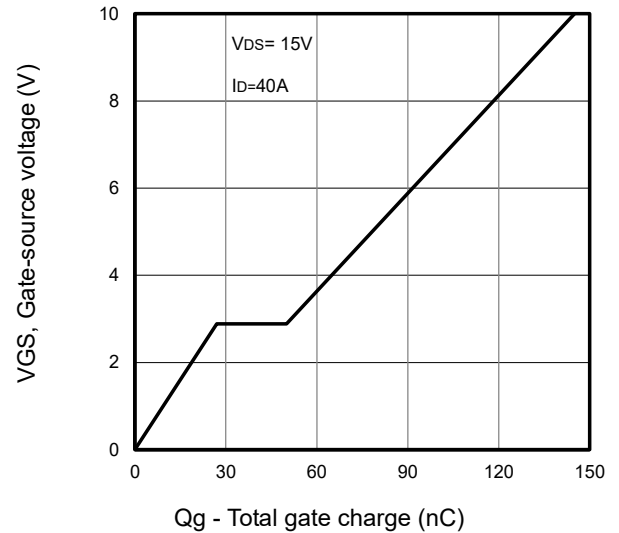


Fig10. Typical gate charge Vs. gate-source voltage

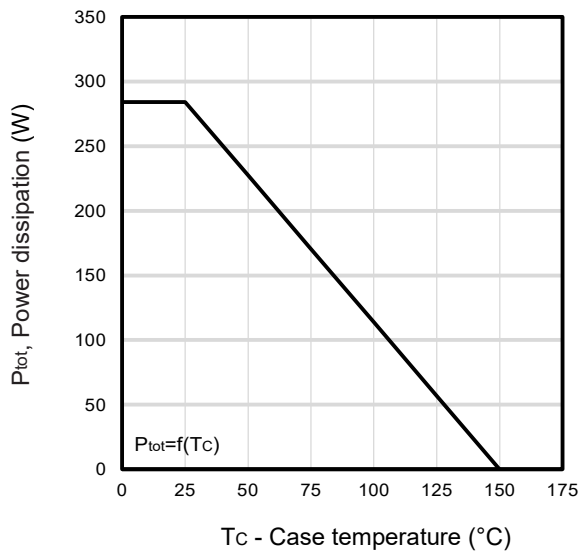


Fig11. Power dissipation Vs. case temperature

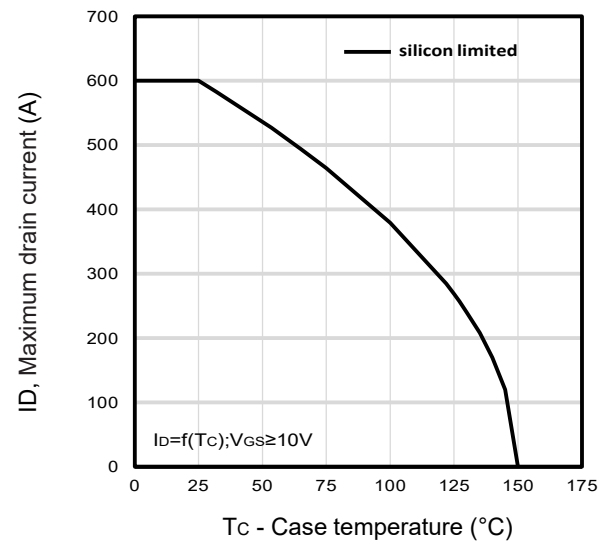
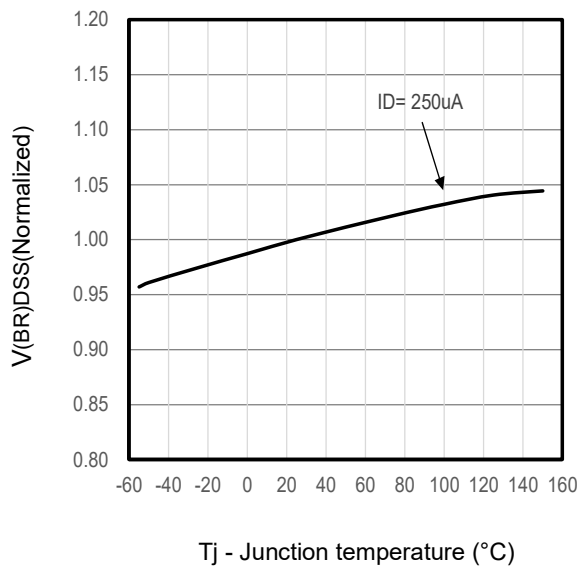
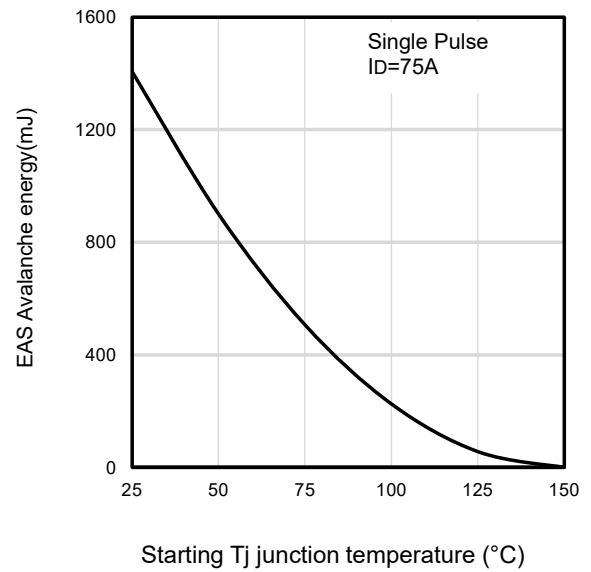
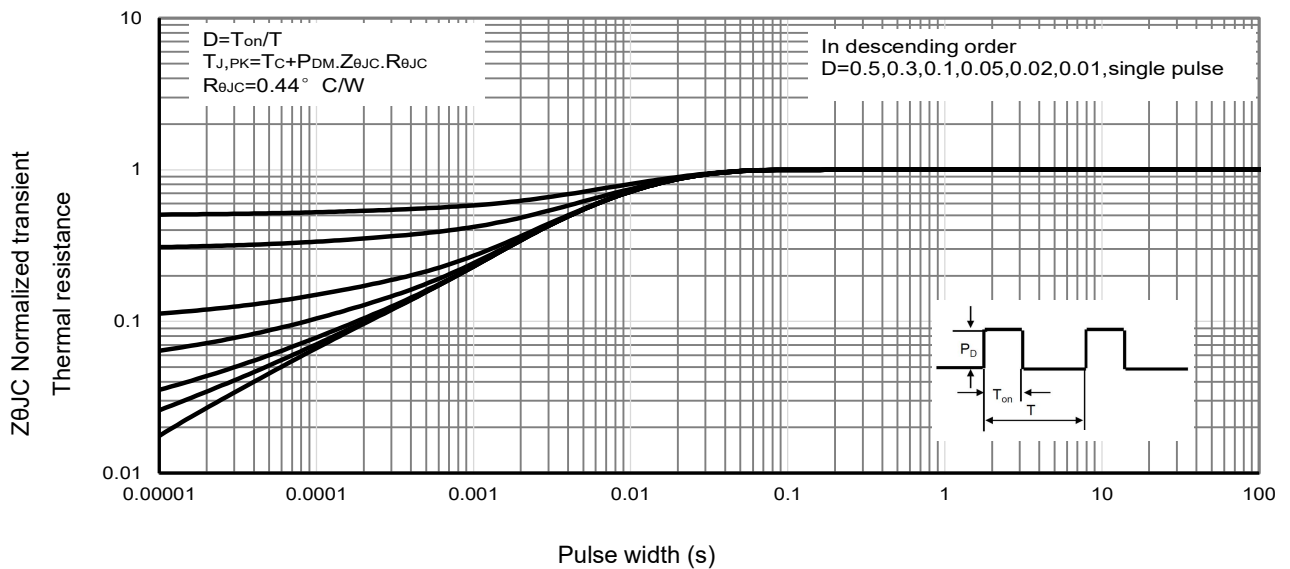
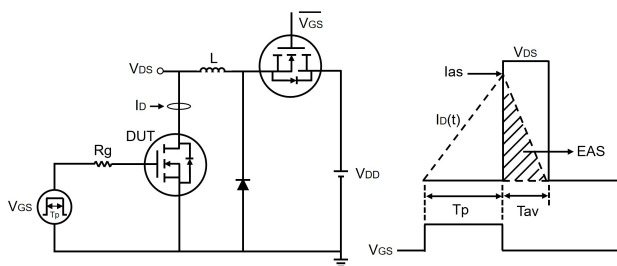
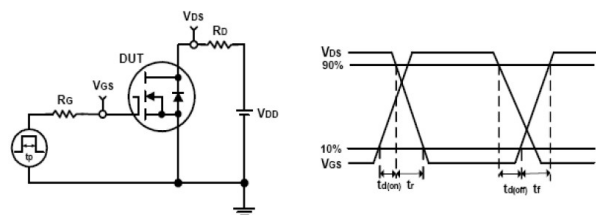
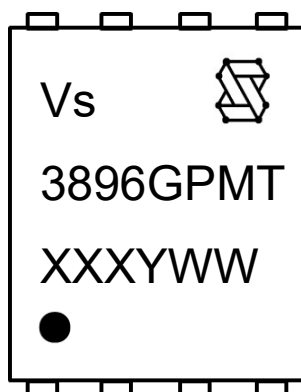


Fig12. Maximum drain current Vs. case temperature

Typical Characteristics


Fig13. Typical $V(BR)DSS$ Vs T_j

Fig14. Maximum avalanche energy vs temperature ($^{\circ}\text{C}$)

Fig15 . Normalized maximum transient thermal impedance

Fig16. Unclamped inductive test circuit and waveforms

Fig17. Switching time test circuit and waveforms

Marking Information



1st line: Vergiga code (Vs), Vergiga logo

2nd line: Part Number (3896GPMT)

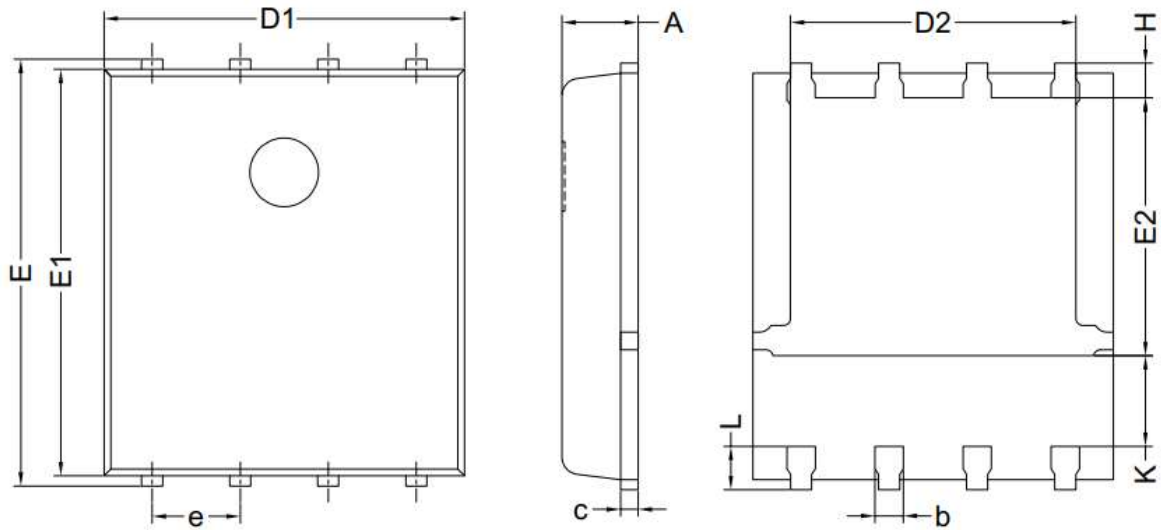
3rd line: Date code (XXXYWW)

XXX: Wafer lot number code, code changed with lot number

Y: Year code, refer to table below

WW: Week code (01 to 53)

Code	C	D	E	F	G	H	J	K	L	M	N	P	Q	R	S	T
Year	2015	2016	2017	2018	2019	2020	2021	2022	2023	2024	2025	2026	2027	2028	2029	2030

PDFN5060X Package Outline Data


Symbol	DIMENSIONS (unit : mm)		
	Min	Typ	Max
A	1.00	1.10	1.20
b	0.33	0.40	0.50
c	0.20	0.25	0.30
D1	5.00	5.20	5.40
D2	3.80	4.10	4.25
e	1.27 BSC		
E	6.00	6.15	6.30
E1	5.76	5.86	5.96
E2	3.52	3.72	3.92
H	0.40	0.50	0.60
K	1.10	--	--
L	0.50	0.60	0.70

